

Notice of References Cited	Application/Control No. 10/618,597	Applicant(s)/Patent Under Reexamination EHRHART, MICHAEL	
	Examiner Uyen-Chau N. Le	Art Unit 2876	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,438,638 B1	08-2002	Jones et al.	710/301
	B	US-6,524,137 B1	02-2003	Liu et al.	439/638
	C	US-6,718,274 B2	04-2004	Huang et al.	710/13
	D	US-6,725,291 B2	04-2004	Lai et al.	710/16
	E	US-6,744,634 B2	06-2004	Yen, Sheng Shun	439/377
	F	US-6,751,694 B2	06-2004	Liu et al.	710/301
	G	US-6,813,164 B2	11-2004	Yen, Sheng Shun	439/76.1
	H	US-6,813,668 B2	11-2004	Tseng et al.	710/301
	I	US-6,820,148 B1	11-2004	Cedar et al.	710/104
	J	US-6,832,281 B2	12-2004	Jones et al.	710/301
	K	US-6,839,864 B2	01-2005	Mambakkam et al.	714/5
	L	US-6,859,856 B2	02-2005	Piau et al.	710/10
	M	US-6,708,230 B2	03-2004	Shin, Hyun-Bae	710/9

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.